

Search Notes

Application/Control No.

10/772,297

Examiner

Sunray Chang

Applicant(s)/Patent under
Reexamination

FUJIBAYASHI ET AL.

Art Unit

2121

SEARCHED

Class	Subclass	Date	Examiner
318	85	3/12/2007	SC

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US_PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/12/2007	SC